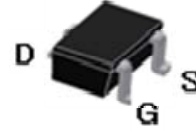
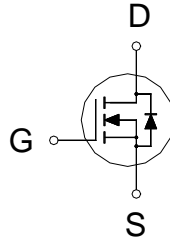




N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

$BV_{DSS}$	100V
$R_{DS(on)} (MAX.)$	220m $\Omega$
$I_D$	1.4A



UIS 100% Tested

Pb-Free Lead Plating & Halogen Free



ABSOLUTE MAXIMUM RATINGS ( $T_C = 25\text{ }^{\circ}\text{C}$  Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$T_C = 25\text{ }^{\circ}\text{C}$	$I_D$	1.4	A
	$T_C = 100\text{ }^{\circ}\text{C}$		0.85	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	5.6	
Power Dissipation	$T_C = 25\text{ }^{\circ}\text{C}$	$P_D$	1.5	W
	$T_C = 100\text{ }^{\circ}\text{C}$		1	
Operating Junction & Storage Temperature Range		$T_{j}, T_{stg}$	-55 to 175	$^{\circ}\text{C}$

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to- Ambient	$R_{\theta JA}$		100	$^{\circ}\text{C} / \text{W}$

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Duty cycle  $\leq 1\%$



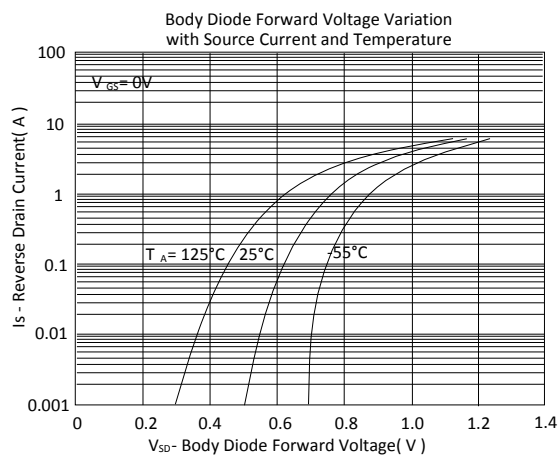
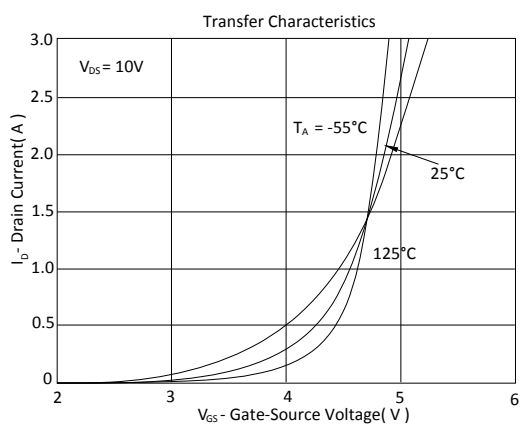
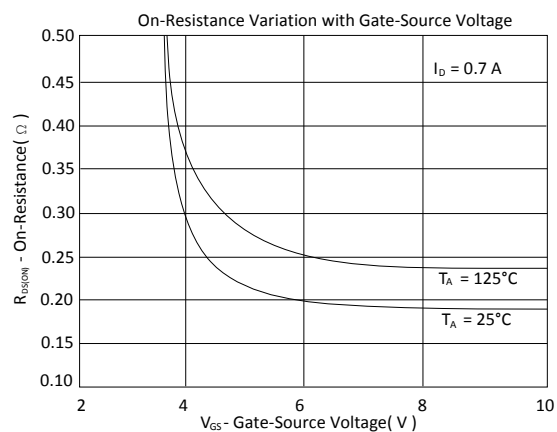
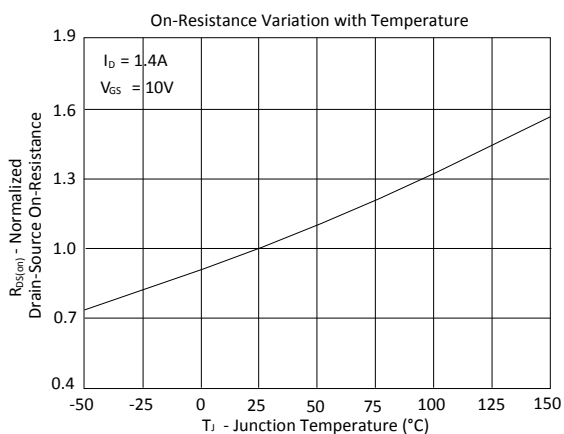
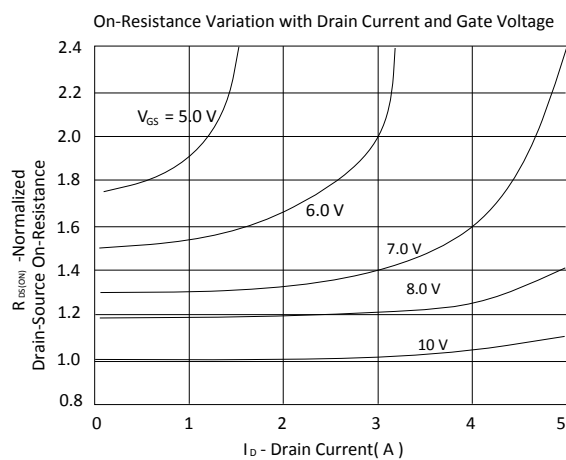
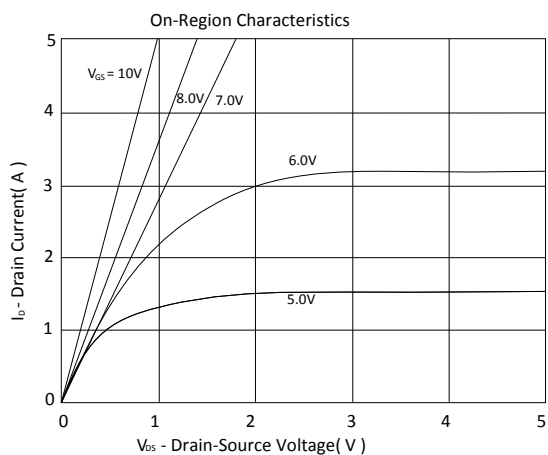
ELECTRICAL CHARACTERISTICS ( $T_c = 25\text{ }^{\circ}\text{C}$ , Unless Otherwise Noted)

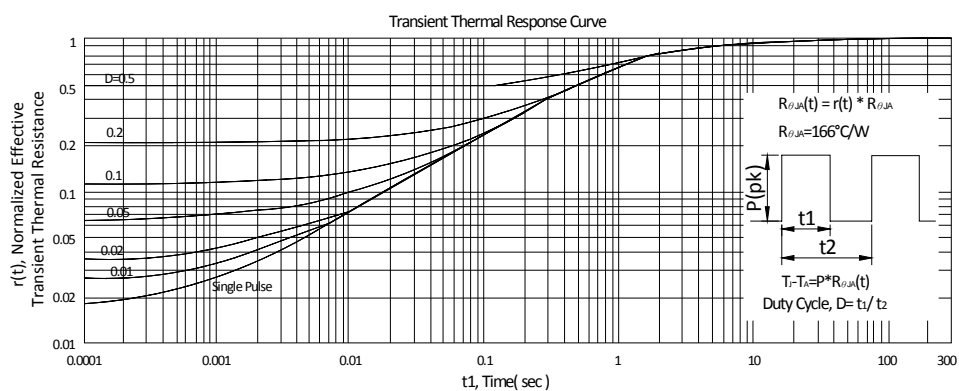
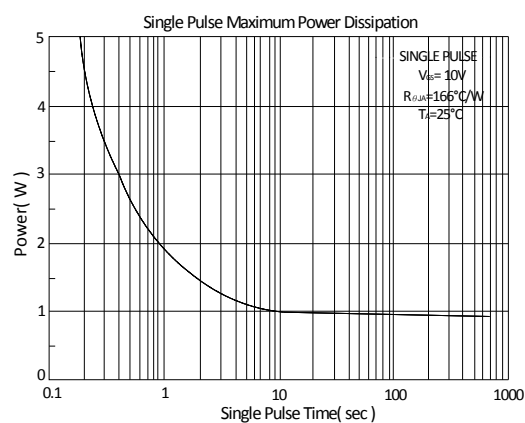
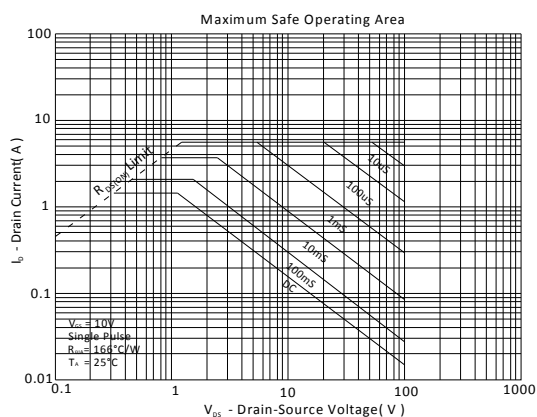
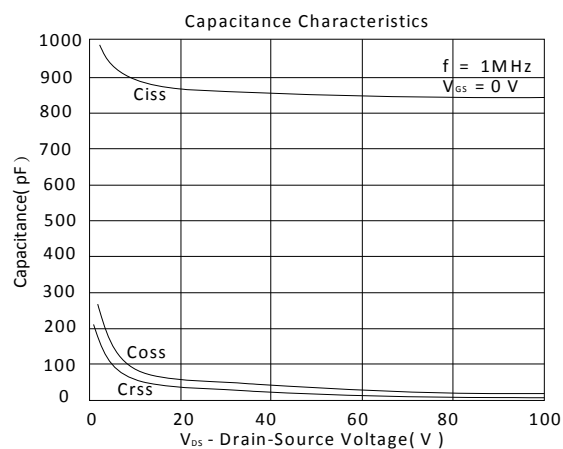
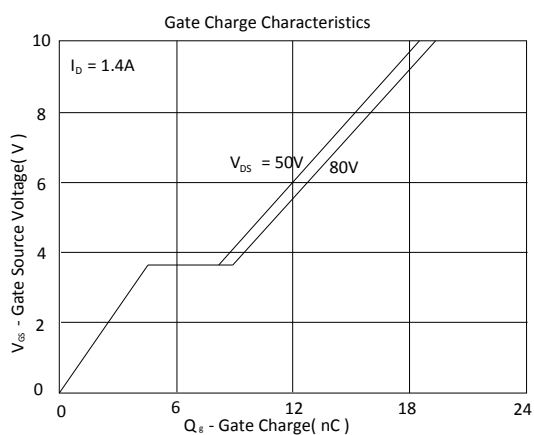
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT	
			MIN	TYP	MAX		
STATIC							
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	100			V	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1	1.5	3		
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 20V$			$\pm 100$	nA	
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 80V, V_{GS} = 0V$			1	$\mu A$	
		$V_{DS} = 70V, V_{GS} = 0V, T_J = 125\text{ }^{\circ}C$			25		
On-State Drain Current <sup>1</sup>	$I_{D(ON)}$	$V_{DS} = 5V, V_{GS} = 10V$	3			A	
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 1.4A$		185	220	m $\Omega$	
		$V_{GS} = 5V, I_D = 0.5A$		205	250		
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 5V, I_D = 1.4A$		4		S	
DYNAMIC							
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 50V, f = 1MHz$		858		pF	
Output Capacitance	$C_{oss}$			22			
Reverse Transfer Capacitance	$C_{rss}$			16			
Total Gate Charge <sup>1,2</sup>	$Q_g$	$V_{DS} = 15V, V_{GS} = 10V,$ $I_D = 1.4A$		20		nC	
Gate-Source Charge <sup>1,2</sup>	$Q_{gs}$			4			
Gate-Drain Charge <sup>1,2</sup>	$Q_{gd}$			5			
Turn-On Delay Time <sup>1,2</sup>	$t_{d(on)}$	$V_{DS} = 15V,$ $I_D = 1A, V_{GS} = 10V, R_{GS} = 6\Omega$		20		nS	
Rise Time <sup>1,2</sup>	$t_r$			40			
Turn-Off Delay Time <sup>1,2</sup>	$t_{d(off)}$			36			
Fall Time <sup>1,2</sup>	$t_f$			30			
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ( $T_c = 25\text{ }^{\circ}C$ )							
Continuous Current	$I_S$				1.4	A	
Pulsed Current <sup>3</sup>	$I_{SM}$				5.6		
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = I_S, V_{GS} = 0V$			1.2	V	
Reverse Recovery Time	$t_{rr}$			50		nS	
Reverse Recovery Charge	$Q_{rr}$			90		nC	

<sup>1</sup>Pulse test : Pulse Width  $\leq 300\text{ }\mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .

<sup>2</sup>Independent of operating temperature.

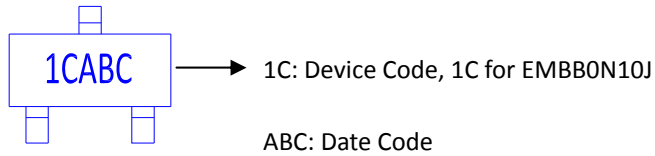
<sup>3</sup>Pulse width limited by maximum junction temperature.



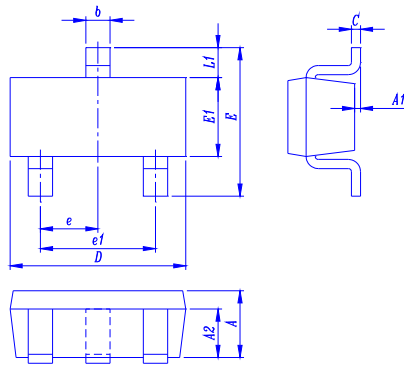


## Ordering & Marking Information:

Device Name: EMBB0N10J for SOT-23



## Outline Drawing



## Dimension in mm

Dimension	A	A1	A2	b	C	D	E	E1	e	e1	L1
Min.	0.85	0		0.30	0.08	2.75	2.6	1.35			0.35
Typ.			0.80						0.95	1.90	
Max.	1.25	0.13		0.50	0.20	3.10	3.0	1.80			0.75

## Footprint

